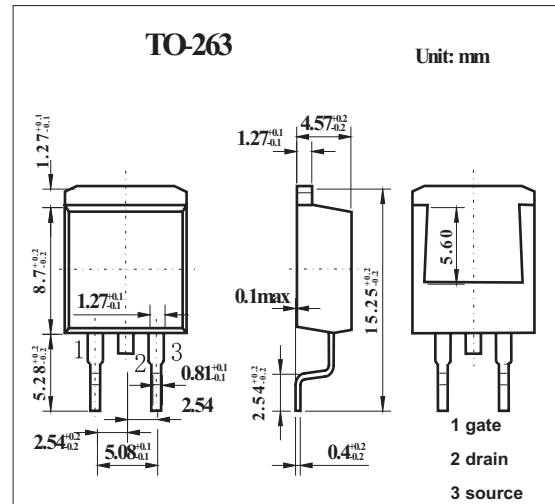
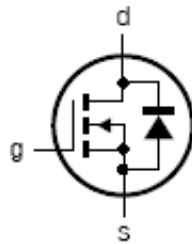


TrenchMOS™ standard level FET

KUK7575-100A

■ Features

- TrenchMOS™ technology
- Q101 compliant
- 175°C rated
- Standard level compatible.

■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

| Parameter | Symbol | Rating | Unit |
|-----------------------------------------------------------------------|----------------|------------|------------------|
| drain-source voltage (DC) | V_{DS} | 100 | V |
| drain-gate voltage (DC) $R_{GS} = 20\text{ k}\Omega$ | V_{DGR} | 100 | V |
| gate-source voltage (DC) | V_{GS} | ± 20 | V |
| drain current (DC) $T_{mb} = 25^\circ\text{C}; V_{GS} = 10\text{ V}$ | I_D | 23 | A |
| drain current (DC) $T_{mb} = 100^\circ\text{C}; V_{GS} = 10\text{ V}$ | | 16.2 | A |
| peak drain current *1 | I_{DM} | 92 | A |
| total power dissipation $T_{mb} = 25^\circ\text{C}$ | P_{tot} | 99 | W |
| storage temperature | T_{stg} | -55 to 175 | $^\circ\text{C}$ |
| operating junction temperature | T_j | -55 to 175 | $^\circ\text{C}$ |
| reverse drain current (DC) $T_{mb} = 25^\circ\text{C}$ | I_{DR} | 23 | A |
| pulsed reverse drain current *2 | I_{DRM} | 92 | A |
| non-repetitive avalanche energy | W_{DSS} | 100 | mJ |
| thermal resistance from junction to ambient | $R_{th(j-a)}$ | 50 | K/W |
| thermal resistance from junction to mounting base | $R_{th(j-mb)}$ | 1.5 | K/W |

*1 $T_{mb} = 25^\circ\text{C}$; pulsed; $t_p \leq 10\ \mu\text{s}$;

*2 unclamped inductive load; $I_D = 14\text{ A}; V_{DS} \leq 100\text{ V}; V_{GS} = 10\text{ V}; R_{GS} = 50\ \Omega$, starting $T_{mb} = 25^\circ\text{C}$

KUK7575-100A

■ Electrical Characteristics Ta = 25°C

| Parameter | Symbol | Testconditions | Min | Typ | Max | Unit |
|--------------------------------------|----------------------|----------------------------------------------------------------------------------------------|-----|------|-----|------|
| drain-source breakdown voltage | V _{(BR)DSS} | I _D = 0.25 mA; V _{GS} = 0 V; T _J = 25°C | 100 | | | V |
| | | I _D = 0.25 mA; V _{GS} = 0 V; T _J = -55°C | 89 | | | V |
| gate-source threshold voltage | V _{GS(th)} | I _D = 1 mA; V _{DS} = V _{GS} ; T _J = 25°C | 2 | 3 | 4 | V |
| | | I _D = 1 mA; V _{DS} = V _{GS} ; T _J = 175°C | 1 | | | V |
| | | I _D = 1 mA; V _{DS} = V _{GS} ; T _J = -55°C | | | 4.4 | V |
| drain-source leakage current | I _{DSS} | V _{DS} = 100 V; V _{GS} = 0 V; T _J = 25°C | | 0.05 | 10 | mA |
| | | V _{DS} = 100 V; V _{GS} = 0 V; T _J = 175°C | | | 500 | mA |
| gate-source leakage current | I _{GSS} | V _{GS} = ±20 V; V _{DS} = 0 V | | 2 | 100 | nA |
| drain-source on-state resistance | R _{DS(on)} | V _{GS} = 10 V; I _D = 13 A; T _J = 25°C | | 64 | 75 | mΩ |
| | | V _{GS} = 10 V; I _D = 13 A; T _J = 175°C | | | 187 | mΩ |
| input capacitance | C _{iss} | V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz | | 907 | | pF |
| output capacitance | C _{oss} | | | 127 | | pF |
| reverse transfer capacitance | C _{rss} | | | 78 | | pF |
| turn-on delay time | t _{d(on)} | | | 8 | | ns |
| rise time | t _r | V _{DD} = 30 V; R _L = 2.2Ω; V _{GS} = 10 V; R _G = 5.6Ω | | 39 | | ns |
| turn-off delay time | t _{d(off)} | | | 26 | | ns |
| fall time | t _f | | | 24 | | ns |
| internal drain inductance | L _d | from drain lead 6 mm from package to centre of die | | 4.5 | | nH |
| | | | | 2.5 | | nH |
| internal source inductance | L _s | from source lead to source bond pad | | 7.5 | | nH |
| source-drain (diode forward) voltage | V _{SD} | I _S = 25 A; V _{GS} = 0 V; | | 0.85 | 1.2 | V |
| reverse recovery time | t _{rr} | I _S = 13 A; di _S /dt = -100 A/μs | | 64 | | ns |
| recovered charge | Q _r | V _{GS} = -10 V; V _{DS} = 30 V | | 120 | | nC |